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TRANSMITTAL FORM (to be used for all correspondence after initial filing)	Application Number	09/943,190
	Filing Date	August 29, 2001
	First Named Inventor	Kristy A. Campbell
	Group Art Unit	2818
	Examiner Name	Unknown
Total Number of Pages in This Submission	Attorney Docket Number MI22-1668	

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TECHNICAL CENTER 2800
August 29, 2001

Patent Application Serial No.
Filing Date
Inventorship Kristy A. Campbell et al.
Assignee Micron Technology, Inc.
Group Art Unit 2818
Examiner Unknown
Attorney's Docket No. MI22-1668
Title: Method of Forming Non-Volatile Resistance Variable Devices, Methods of
Forming a Programmable Memory Cell of Memory Circuitry, and a Non-
Volatile Resistance Variable Device

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. Copies of the cited art are attached hereto. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed within three months of the filing date of the application or before the mailing of a first Office Action, whichever occurs last. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Dated: 10-8-02

By: [Signature]
Mark S. Matkin
Reg. No. 32,268

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U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	3,622,319	11/23/71	Sharp	96	27	
	AB	3,743,847	07/03/73	Boland	250	510	
	AC	4,269,935	05/26/81	Masters et al.	430	323	
	AD	4,312,938	01/26/82	Drexler et al.	430	496	
	AE	4,320,191	03/16/82	Yoshikawa et al.	430	296	
	AF	4,795,657	01/03/89	Formigoni et al.	427	96	
	AG	4,847,674	07/11/89	Silwa et al.	357	67	
	AH	5,177,567	01/05/93	Klersy et al.	257	4	
	AI	5,219,788	06/15/93	Abernathey et al.	437	187	
	AJ	5,726,083	03/10/98	Takaishi	438	210	
	AK	5,751,012	05/12/98	Wolstenholme et al.	257	5	

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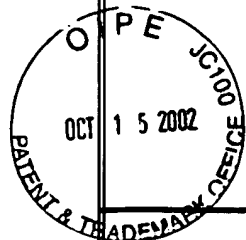
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	AN		Das et al., <i>Theory of the characteristic curves of the silver chalcogenide glass inorganic photoresists</i> , 54 APPL. PHYS. LETT., No. 18, pp. 1745-1747 (May 1989).
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	AA	5,789,277	08/04/98	Zahorik et al.	438	95	
	AB	5,841,150	11/24/98	Gonzalez et al.	257	3	
	AC	5,920,788	07/06/99	Reinberg	438	466	
	AD	5,998,066	12/07/99	Block et al.	430	5	
	AE	6,077,729	06/20/00	Harshfield	438	128	
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	AP		Kawaguchi et al., <i>Mechanism of photosurface deposition</i> , 164-166 J. NON-CRYST. SOLIDS, pp. 1231-1234 (1993).

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	AN		McHardy et al., <i>The dissolution of metals in amorphous chalcogenides and the effects of electron and ultraviolet radiation</i> , 20 J. PHYS. C: SOLID STATE PHYS., pp. 4055-4075 (1987).
	AO		Miyatani, <i>Electrical Properties of Ag₂Se</i> , 13 J. Phys. Soc. Japan, p. 317 (1958).
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	AA	10/077,867		Campbell et al. (as filed)			02/20/2002
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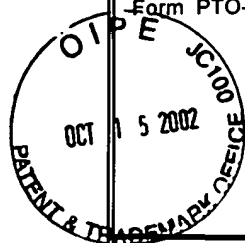
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	AO		Safran et al., <i>TEM study of Ag₂Se developed by the reaction of polycrystalline silver films and selenium</i> , 317 THIN SOLID FILMS, pp. 72-76 (1998).
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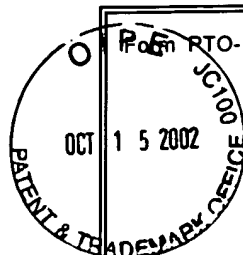
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	AN		Somogyi et al., <i>Temperature Dependence of the Carrier Mobility in Ag₂Se Layers Grown on NaCl and SiO_x Substrates</i> , 74 ACTA PHYSICA HUNGARICA, No. 3, pp. 243-255 (1994).				
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	AN		West, DISSERTATION: <i>Electrically Erasable Non-Volatile Memory Via electrochemical Deposition of Multifractal Aggregates</i> , Arizona State University, pp. title page-168 (UMI Co., May 1998).
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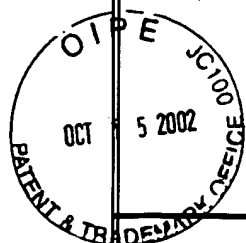
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AN		Yoshikawa et al., <i>Dry development of Se-Ge Inorganic photoresist</i> , 36 APPL. PHYS. LETT., No. 1, pp. 107-109 (January 1980).
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